

# **Structured Electronic Design**

EE3C11

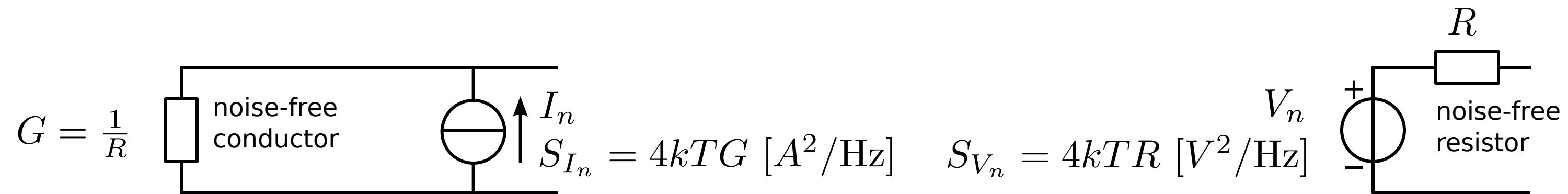
Noise in Electronic Circuits

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# Noise mechanisms

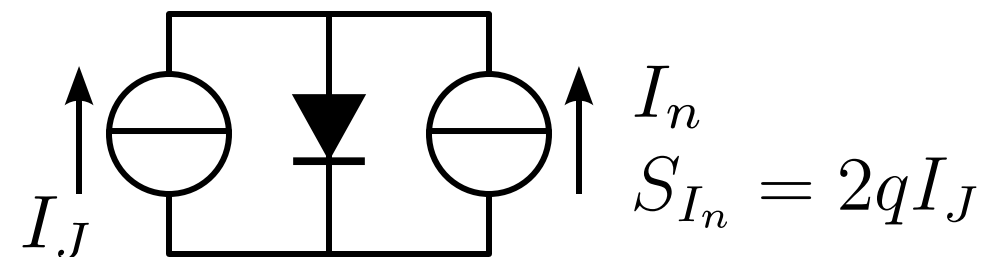
## Thermal noise

Noise in conductors caused by thermal (Brownian) motion (Brown 1828).  
Experimentally detected by Johnson (1928) and explained by Nyquist (1928).



## Shot noise

Noise current associated with a DC current through a junction.



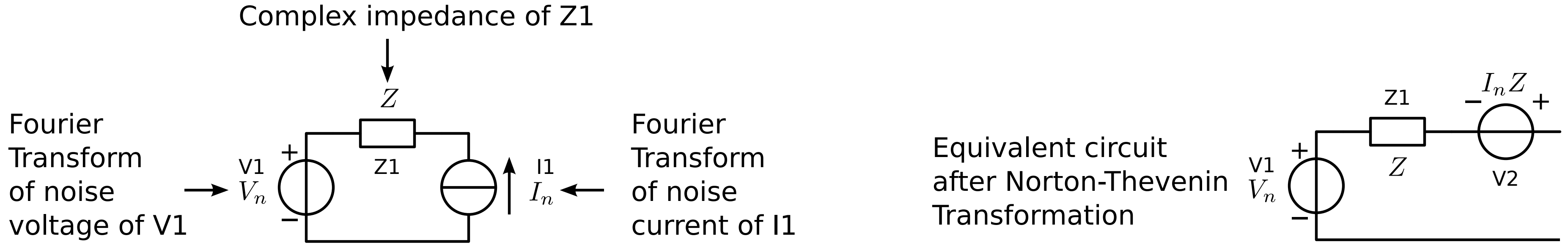
## Excess noise

Noise current resulting from fluctuations in conduction mechanism.

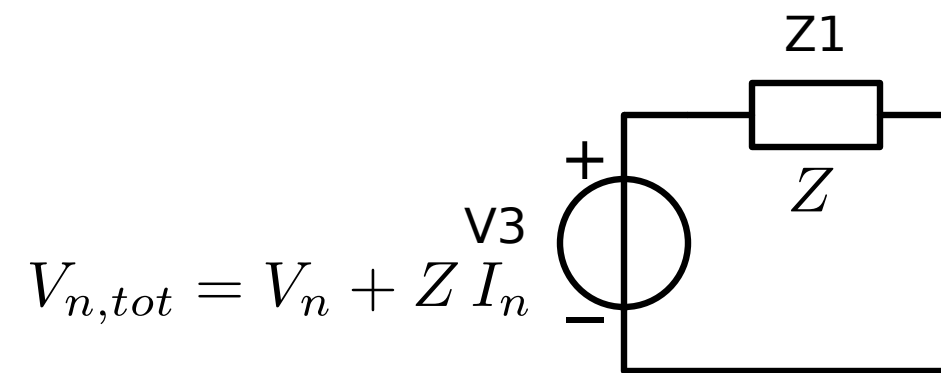
**In junctions**  $S_{I_n} = K \frac{I_J^\alpha}{f}$

**In resistors**  $S_{V_n} = K \frac{V_R^2}{f}$

# Drawing conventions



Equivalent circuit in which the voltage of  $V_3$  represents the total noise voltage



# Noise parameters

## Equivalent noise bandwidth of a system

Bandwidth of a brickwall filter with pass-band gain equal to the maximum magnitude of the system transfer that would produce

the same output noise power as the system:  $B_n = \frac{1}{2\pi} \int_0^\infty \left| \frac{H(j\omega)}{H_{\max}} \right|^2 d\omega [\text{Hz}]$

## Noise temperature

Apparent temperature of a noise source with available noise power  $P$  over bandwidth  $B$ :  $T_n = \frac{P}{kB}$

## Signal-to-noise ratio

dB ratio of (weighted) signal power and (weighted) noise power:

$$SNR = 10 \log_{10} \left( \frac{P_{\text{signal}}}{P_{\text{noise}}} \right)$$

## Noise figure

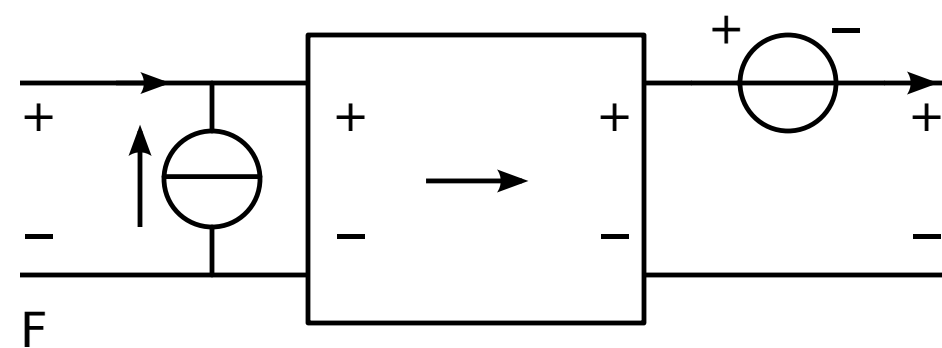
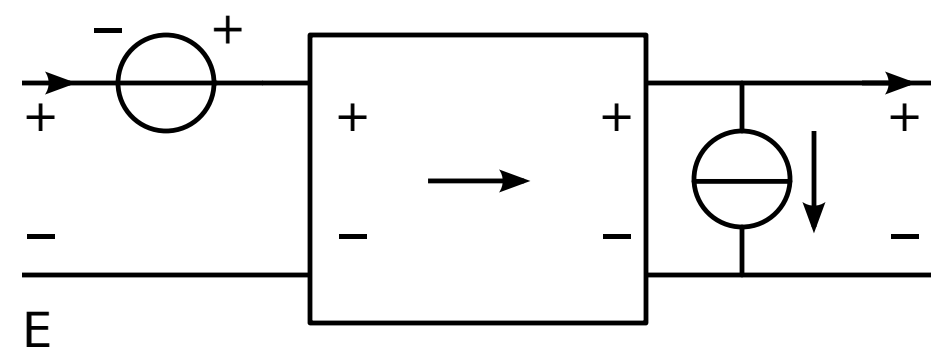
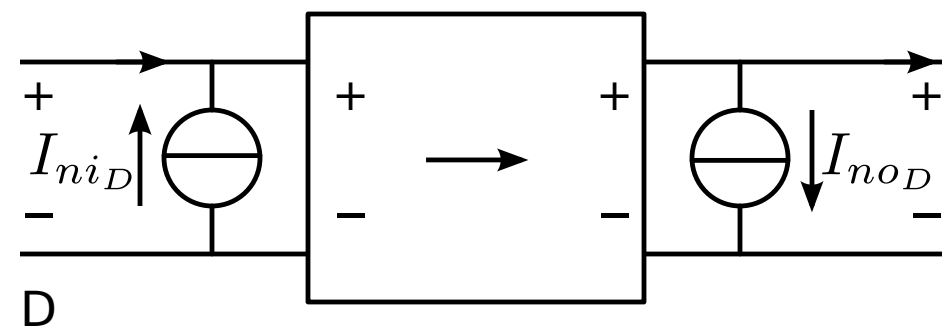
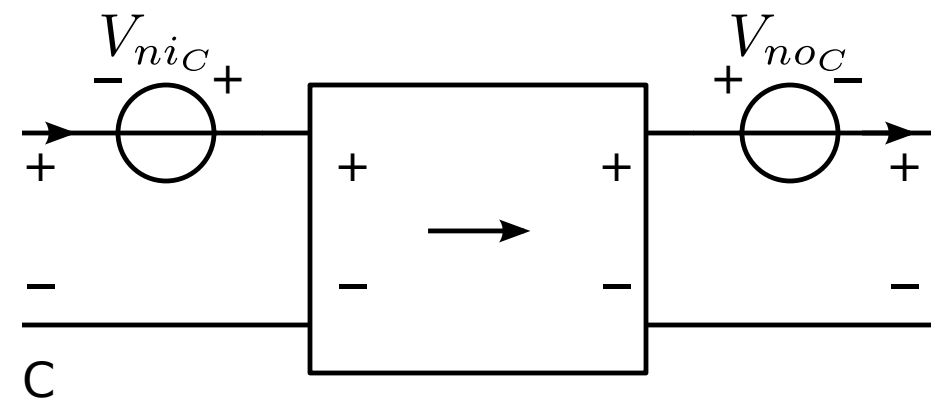
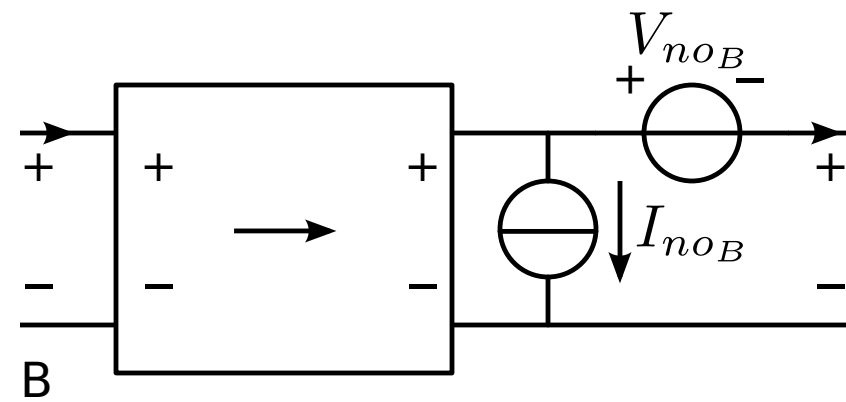
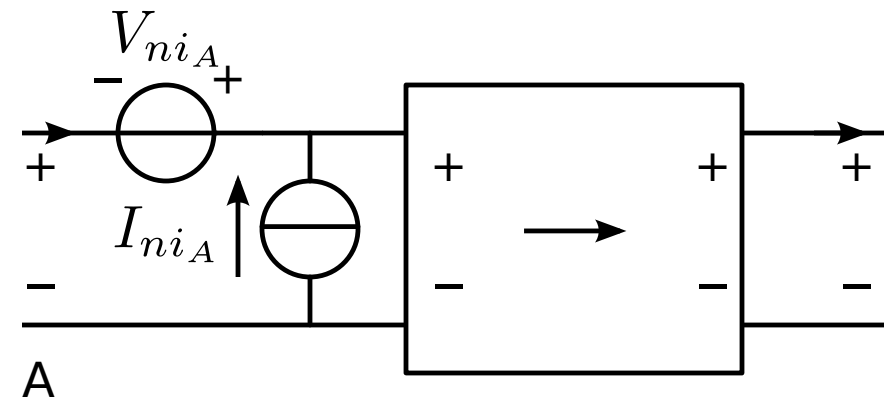
dB measure for deterioration of the signal-to-noise ratio by a system:

$$F = SNR_{\text{input}} - SNR_{\text{output}}$$

## Dynamic range

dB ratio of maximum signal power and the noise power in the absence of a signal:  $D = 10 \log_{10} \left( \frac{P_{s,\max}}{P_{n,\min}} \right)$

# Noisy two-ports



## Noise representation

- A noise-free two-port with two noise sources
- Six representations:
  - 4 port variables:
    - \* two independent variables
    - \* two dependent variables

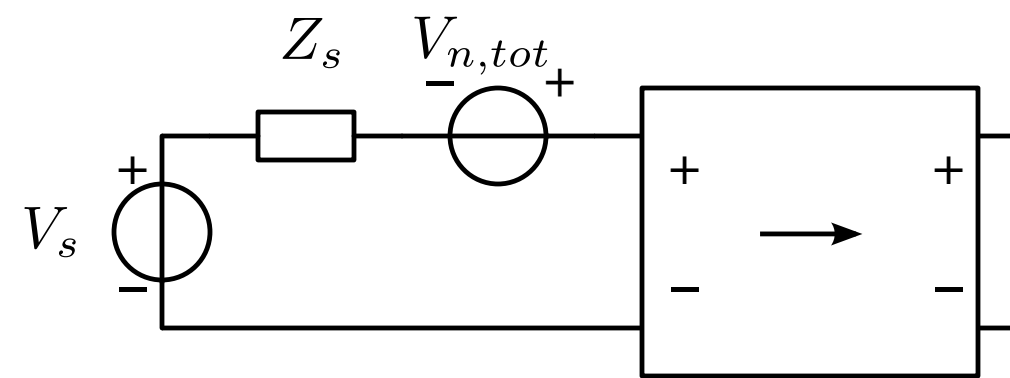
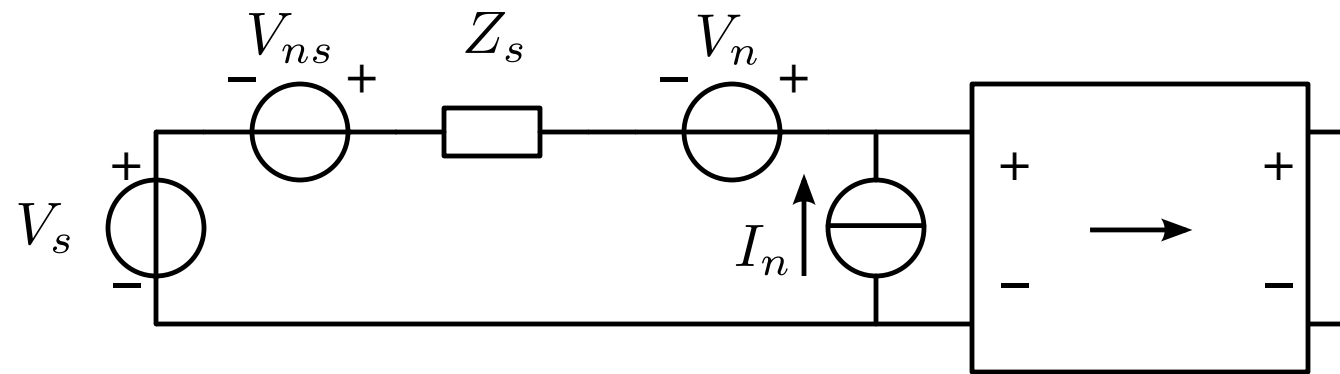
## Can be translated into each other

- Example 2.9
- Example 19.2

# Amplifier noise design

Equivalent-input noise description is convenient at early stages of the design.

Budgets for equivalent input noise sources can be determined without knowledge of amplifier circuit.



$$S_{V_{n,tot}} = S_{V_{ns}} + S_{V_n} + S_{I_n} |Z_s|^2$$

Noise figure  
equivalent-input notation:

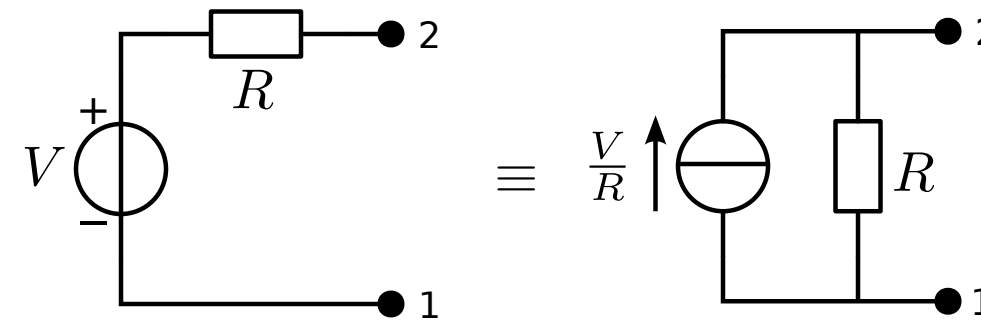
$$F = \frac{\int_0^\infty S_{V_{n,tot}} |W(f)|^2 df}{\int_0^\infty S_{V_{ns}} |W(f)|^2 df}$$

$$|W(f)|^2$$

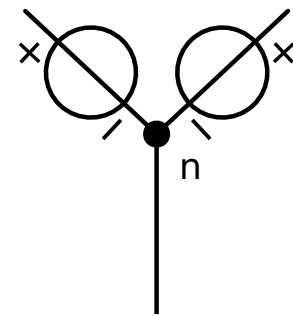
Squared magnitude of weighting function that models the sensitivity of the observer as a function of frequency

# Source transformation techniques

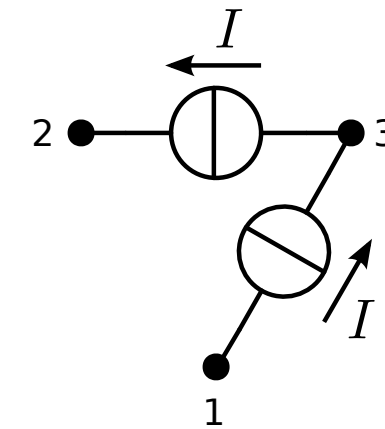
Thévenin / Norton equivalent networks



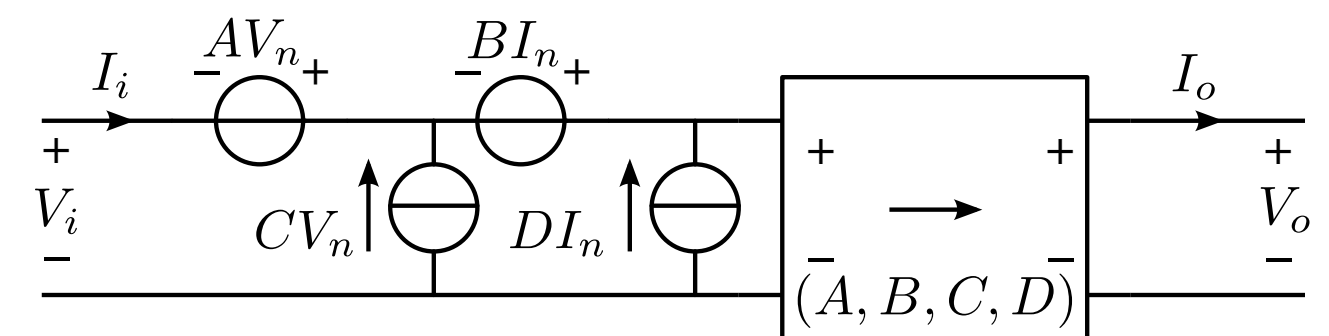
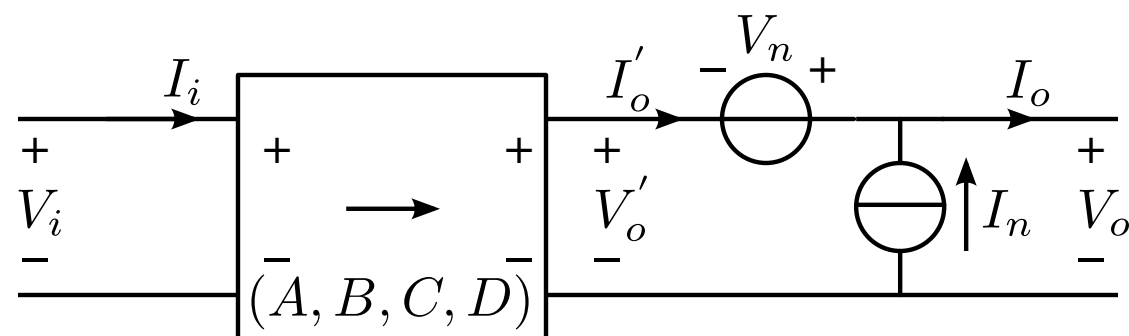
Blakesley voltage shift



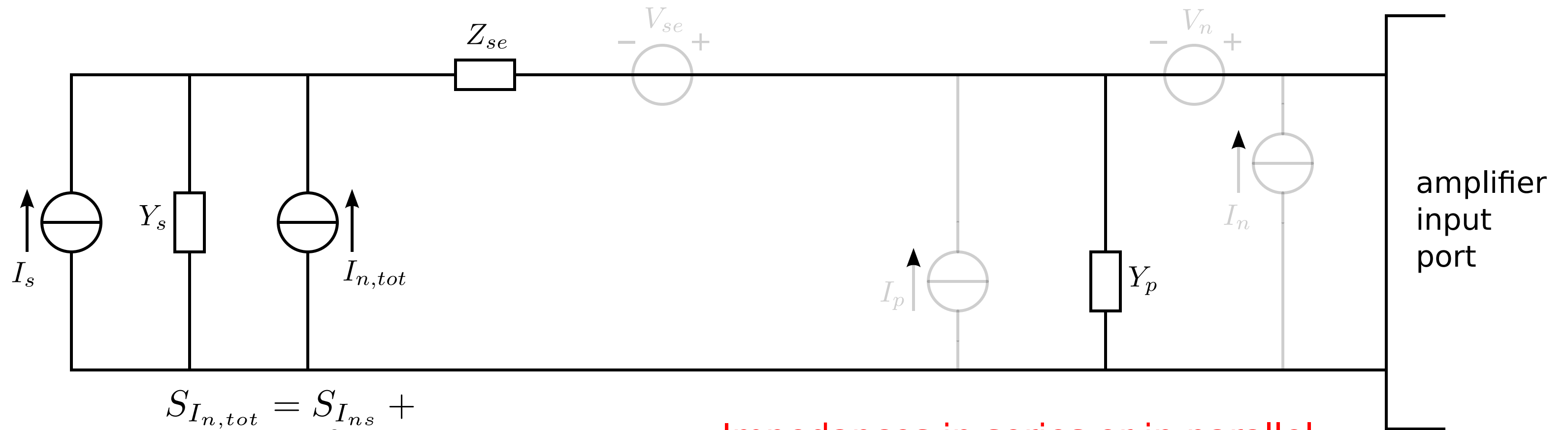
Current split / redirect



Equivalent two-port representations



# Impedances in the signal path



$$\begin{aligned}
 S_{I_{n,tot}} = & S_{I_{ns}} + \\
 & + S_{V_{se}} |Y_s|^2 + \\
 & + S_{I_n} |1 + Z_{se} Y_s|^2 + \\
 & + S_{V_n} |Y_p + Y_s (1 + Y_p Z_{se})|^2 + \\
 & + S_{I_p} |1 + Z_{se} Y_s|^2
 \end{aligned}$$

Impedances in series or in parallel with the signal path increase the influence of noise sources further in the signal path



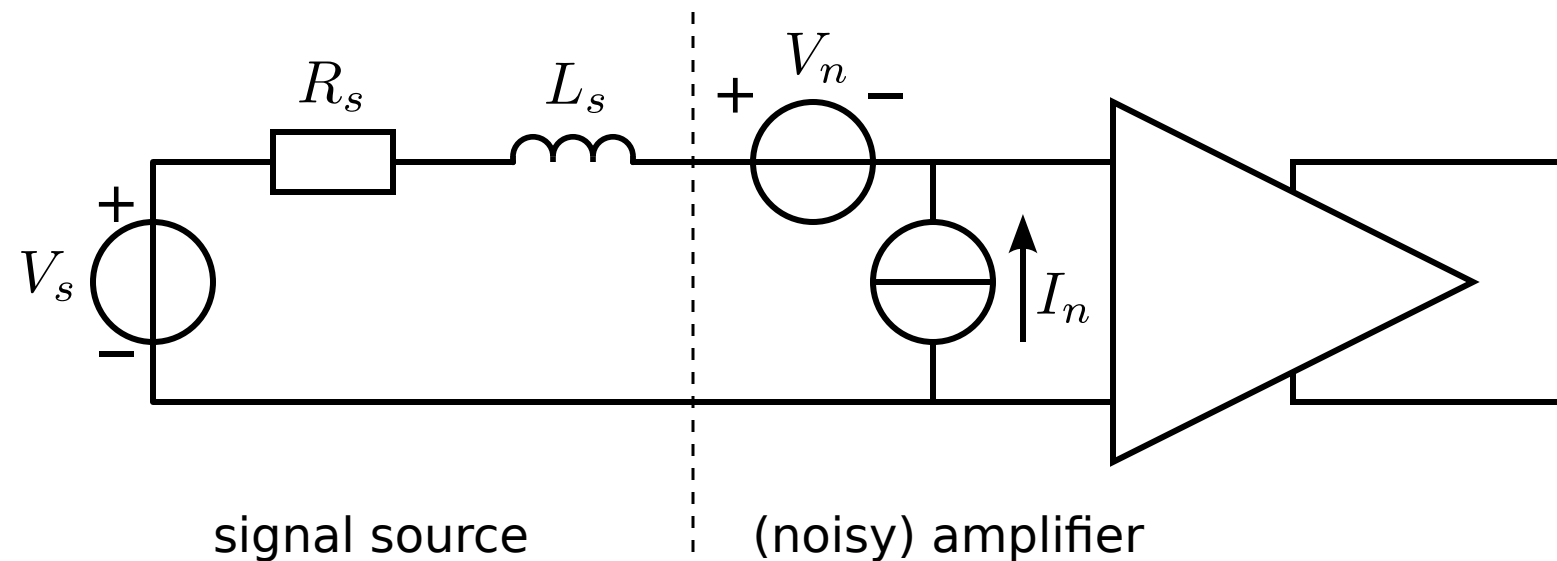
# Design conclusions

Insertion of impedances in series or in parallel with the signal path should be avoided

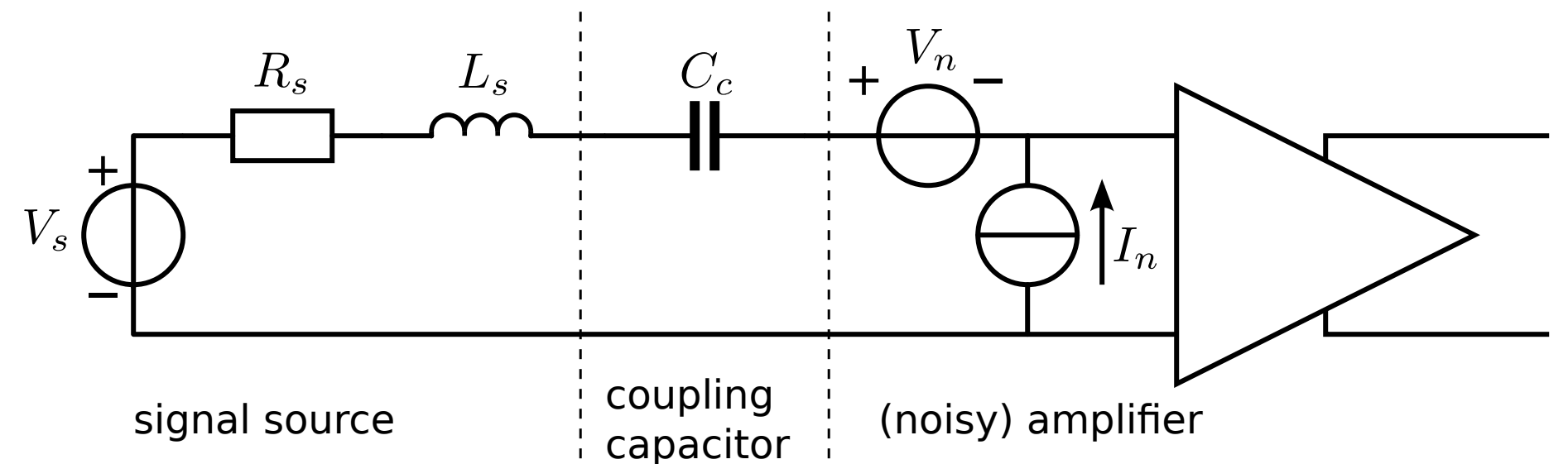
Generally, they increase the influence of existing noise sources

If these impedances have a nonzero real part they contribute noise themselves

Only in narrow-band applications they may improve the noise performance:



$$S_{V_{n_{tot}}} = 4kTR_s + S_{V_n} + S_{I_n} \left( R_s^2 + (\omega L_s)^2 \right)$$



$$S_{V_{n_{tot}}} = 4kTR_s + S_{V_n} + S_{I_n} \left( R_s^2 + \left( \omega L_s - \frac{1}{\omega C_c} \right)^2 \right)$$

Strong reduction of contribution of  $I_n$  to the total source-referred noise if  $\omega L_s \approx \frac{1}{\omega C_c}$